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November 2015

## FODM121 Series, FODM124, FODM2701, FODM2705

# 4-Pin Full Pitch Mini-Flat Package Phototransistor Optocouplers

#### **Features**

- · More than 5 mm Creepage/Clearance
- Compact 4-Pin Surface Mount Package (2.4 mm Maximum Standoff Height)
- · Current Transfer Ratio in Selected Groups:

DC Input:

FODM121: 50–600% FODM121A: 100–300% FODM121B: 50–150% FODM121C: 100–200% FODM124: 100% MIN FODM2701: 50–300%

AC Input:

FODM2705: 50-300%

- · Safety and Regulatory Approvals:
  - UL1577, 3,750 VAC<sub>RMS</sub> for 1 Minute
  - DIN-EN/IEC60747-5-5, 565 V Peak Working Insulation Voltage

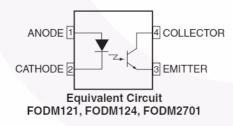
### **Applications**

- · Digital Logic Inputs
- · Microprocessor Inputs
- Power Supply Monitor
- · Twisted Pair Line Receiver
- · Telephone Line Receiver

### Description

The FODM121 series, FODM124, and FODM2701 consists of a gallium arsenide infrared emitting diode driving a phototransistor in a compact 4-pin mini-flat package. The lead pitch is 2.54 mm. The FODM2705 consists of two gallium arsenide infrared emitting diodes connected in inverse parallel for AC operation.

## Functional Block Diagram



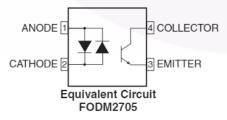


Figure 1. Schematic

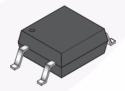


Figure 2. Package Outlines

## Safety and Insulation Ratings

As per DIN EN/IEC 60747-5-5, this optocoupler is suitable for "safe electrical insulation" only within the safety limit data. Compliance with the safety ratings shall be ensured by means of protective circuits.

Parameter	Characteristics	
Installation Classifications per DIN VDE	< 150 V <sub>RMS</sub>	I–IV
0110/1.89 Table 1, For Rated Mains Voltage	< 300 V <sub>RMS</sub>	I–III
Climatic Classification		40/110/21
Pollution Degree (DIN VDE 0110/1.89)		2
Comparative Tracking Index		175

Symbol	Parameter	Value	Unit
V	Input-to-Output Test Voltage, Method A, $V_{IORM}$ x 1.6 = $V_{PR}$ , Type and Sample Test with $t_m$ = 10 s, Partial Discharge < 5 pC	904	$V_{peak}$
V <sub>PR</sub>	Input-to-Output Test Voltage, Method B, $V_{IORM}$ x 1.875 = $V_{PR}$ , 100% Production Test with $t_m$ = 1 s, Partial Discharge < 5 pC	1060	V <sub>peak</sub>
V <sub>IORM</sub>	Maximum Working Insulation Voltage	565	$V_{peak}$
V <sub>IOTM</sub>	Highest Allowable Over-Voltage	6000	V <sub>peak</sub>
	External Creepage	≥ 5	mm
	External Clearance	≥ 5	mm
DTI	Distance Through Insulation (Insulation Thickness)	≥ 0.4	mm
T <sub>S</sub>	Case Temperature <sup>(1)</sup>	150	°C
I <sub>S,INPUT</sub>	Input Current <sup>(1)</sup>	200	mA
P <sub>S,OUTPUT</sub>	Output Power <sup>(1)</sup>	300	mW
R <sub>IO</sub>	Insulation Resistance at T <sub>S</sub> , V <sub>IO</sub> = 500 V <sup>(1)</sup>	> 10 <sup>9</sup>	Ω

#### Note:

1. Safety limit values - maximum values allowed in the event of a failure.

## **Absolute Maximum Ratings**

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.  $T_A = 25^{\circ}C$  Unless otherwise specified.

Symbol	Para	Value	Unit	
TOTAL PACK	\GE			
T <sub>STG</sub>	Storage Temperature		-40 to +125	°C
T <sub>OPR</sub>	Operating Temperature		-40 to +110	°C
TJ	Junction Temperature		-40 to +125	°C
T <sub>SOL</sub>	Lead Solder Temperature		260 for 10 sec	°C
MITTER			,	
I <sub>F (avg)</sub>	Continuous Forward Current	Continuous Forward Current		
I <sub>F (pk)</sub>	Peak Forward Current (1 µs pu	lse, 300 pps.)	1	А
V <sub>R</sub>	Reverse Voltage	Reverse Voltage		V
В	Power Dissipation		70	mW
$P_D$	Derate linearly (Above 75°C)		1.41	mW/°C
ETECTOR				
I <sub>C</sub>	Continuous Collector Current		80	mA
V <sub>CEO</sub>	Collector-Emitter Voltage	FODM121 Series, FODM124	80	1/
		FODM2701, FODM2705	40	V
V <sub>ECO</sub>	Emitter-Collector Voltage		6	V
	Power Dissipation		150	mW
$P_D$	Derate linearly (Above 80°C)	3.27	mW/°C	

## **Electrical Characteristics**

 $T_A$  = 25°C unless otherwise specified.

Symbol	Parameter	Device	Test Conditions	Min.	Тур.	Max.	Unit	
INDIVIDU	AL COMPONENT CHAR	ACTERISTICS						
Emitter								
V <sub>F</sub> Forwa		FODM121 Series, FODM124	I <sub>F</sub> = 10 mA	1.0		1.3	V	
	Forward Voltage	FODM2701	I <sub>F</sub> = 5 mA			1.4		
		FODM2705	I <sub>F</sub> = ±5 mA					
I <sub>R</sub>	Reverse Current	FODM121 Series, FODM124, FODM2701	V <sub>R</sub> = 5 V			5	μA	
Detecto								
D) /	Collector-Emitter	FODM121 Series, FODM124		80				
BV <sub>CEO</sub>	Breakdown Voltage	FODM2701, FODM2705	- I <sub>C</sub> = 1 mA, I <sub>F</sub> = 0	40			V	
BV <sub>ECO</sub>	Emitter-Collector Breakdown Voltage	All	I <sub>E</sub> = 100 μA, I <sub>F</sub> = 0	7			V	
I <sub>CEO</sub>	Collector Dark Current	All	V <sub>CE</sub> = 40 V, I <sub>F</sub> = 0			100	nA	
C <sub>CE</sub>	Capacitance	All	V <sub>CE</sub> = 0 V, f = 1 MHz		10		pF	
TRANSF	R CHARACTERISTICS							
		FODM2701	I <sub>F</sub> = 5 mA, V <sub>CE</sub> = 5 V	50		300		
	DC Current Transfer	FODM2705	$I_F = \pm 5 \text{ mA}, V_{CE} = 5 \text{ V}$	50		300	%	
		FODM121		50		600		
CTD		FODM121A	1 - 5 4 \/ - 5 \/	100		300		
CTR	Ratio	FODM121B	$I_F = 5 \text{ mA}, V_{CE} = 5 \text{ V}$	50		150		
		FODM121C		100		200	1	
		FODM124	I <sub>F</sub> = 1 mA, V <sub>CE</sub> = 0.5 V	100		1200		
			I <sub>F</sub> = 0.5 mA, V <sub>CE</sub> = 1.5 V	50				
	CTR Symmetry	FODM2705	I <sub>F</sub> = ±5 mA, V <sub>CE</sub> = 5 V	0.3		3.0	/	
	Saturation Voltage	FODM121 Series	I <sub>F</sub> = 8 mA, I <sub>C</sub> = 2.4 mA			0.4	V	
.,		FODM124	I <sub>F</sub> = 1 mA, I <sub>C</sub> = 0.5 mA			0.4		
V <sub>CE</sub> (SAT)		FODM2701	I <sub>F</sub> = 10 mA, I <sub>C</sub> = 2 mA			0.3		
		FODM2705	I <sub>F</sub> = ±10 mA, I <sub>C</sub> = 2 mA			0.3		
t <sub>r</sub>	Rise Time (Non-Saturated)	All	$I_C = 2 \text{ mA}, V_{CE} = 5 \text{ V},$ $R_L = 100 \Omega$		3		μs	
t <sub>f</sub>	Fall Time (Non-Saturated)	All	$I_C$ = 2 mA, $V_{CE}$ = 5 V, $R_L$ = 100 $\Omega$		3		μs	
ISOLATIO	N CHARACTERISTICS							
V <sub>ISO</sub>	Steady State Isolation Voltage <sup>(2)</sup>	All	1 minute	3750			VAC <sub>RN</sub>	

#### Note:

2. Steady state isolation voltage, V<sub>ISO</sub>, is an internal device dielectric breakdown rating. For this test, pins 1 and 2 are common, and pins 3 and 4 are common.

## **Typical Performance Curves**

 $T_A = 25$ °C unless otherwise specified.

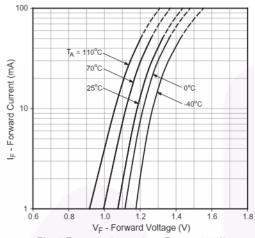


Fig. 3 Forward Current vs. Forward Voltage

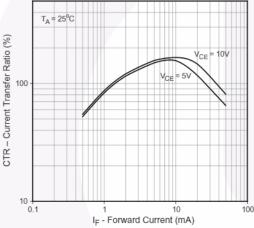


Fig. 5 Current Transfer Ratio vs. Forward Current (FODM121/2701/2705)

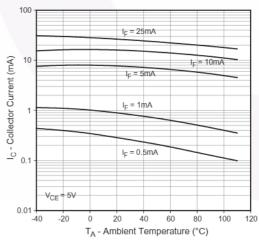


Fig. 7 Collector Current vs. Ambient Temperature (FODM121/2701/2705)

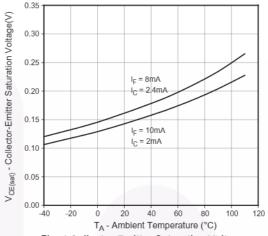


Fig. 4 Collector-Emitter Saturation Voltage vs. Ambient Temperature (FODM121/2701/2705)

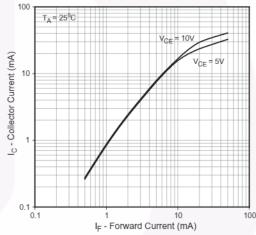


Fig. 6 Collector Current vs. Forward Current (FODM121/2701/2705)

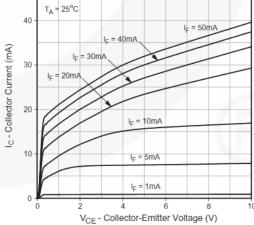


Fig. 8 Collector Current vs. Collector-Emitter Voltage (FODM121/2701/2705)

## Typical Performance Curves (Continued)

 $T_A = 25$ °C unless otherwise specified.

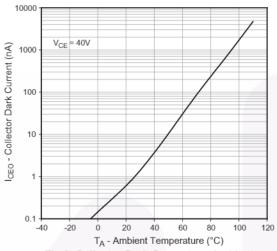


Fig 9. Collector Dark Current vs. Ambient Temperature (FODM121/2701/2705)

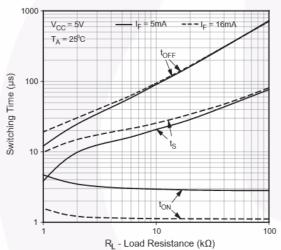


Fig. 11 Switching Time vs. Load Resistance (FODM121/2701/2705)

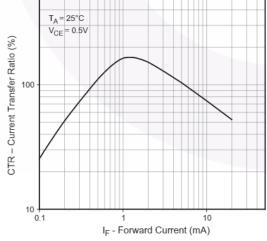


Fig. 13 Current Transfer Ratio vs. Forward Current (FODM124)

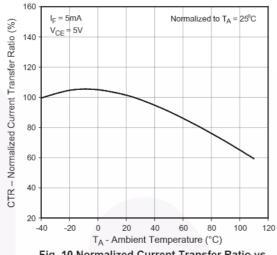


Fig. 10 Normalized Current Transfer Ratio vs. Ambient Temperature (FODM121/2701/2705)

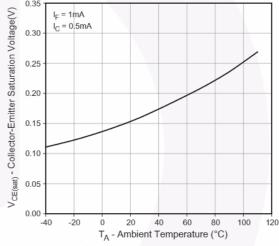


Fig. 12 Collector-Emitter Saturation Voltage vs. Ambient Temperature (FODM124)

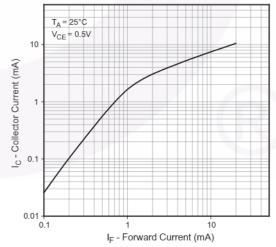


Fig 14. Collector Current vs. Forward Current (FODM124)

## Typical Performance Curves (Continued)

 $T_A = 25$ °C unless otherwise specified.

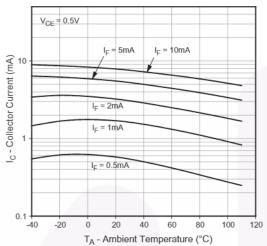


Fig 15. Collector Current vs. Ambient Temperature (FODM124)

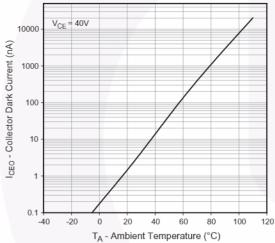


Fig. 17 Collector Dark Current vs. Ambient Temperature (FODM124)

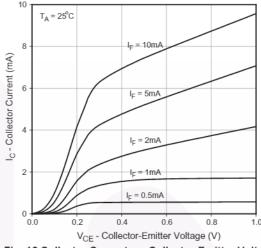


Fig. 16 Collector Current vs. Collector-Emitter Voltage (FODM124)

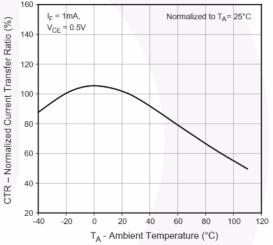


Fig. 18 Normalized Current Transfer Ratio vs.
Ambient Temperature (FODM124)

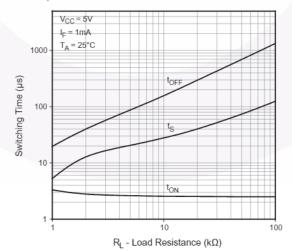
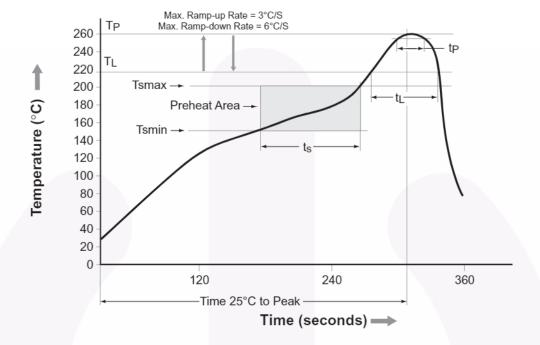


Fig. 19 Switching Time vs. Load Resistance (FODM124)

## **Reflow Profile**



Profile Freature	Pb-Free Assembly Profile	
Temperature Min. (Tsmin)	150°C	
Temperature Max. (Tsmax)	200°C	
Time (t <sub>S</sub> ) from (Tsmin to Tsmax)	60-120 seconds	
Ramp-up Rate (t <sub>L</sub> to t <sub>P</sub> )	3°C/second max.	
Liquidous Temperature (T <sub>L</sub> )	217°C	
Time (t <sub>L</sub> ) Maintained Above (T <sub>L</sub> )	60–150 seconds	
Peak Body Package Temperature	260°C +0°C / -5°C	
Time (t <sub>P</sub> ) within 5°C of 260°C	30 seconds	
Ramp-down Rate (T <sub>P</sub> to T <sub>L</sub> )	6°C/second max.	
Time 25°C to Peak Temperature	8 minutes max.	

## **Ordering Information**

Part Number	Package	Packing Method
FODM121	Full Pitch Mini-Flat 4-Pin	Tube (100 units)
FODM121R2	Full Pitch Mini-Flat 4-Pin	Tape and Reel (2500 Units)
FODM121V	Full Pitch Mini-Flat 4-Pin, DIN EN/IEC60747-5-5 Option	Tube (100 Units)
FODM121R2V	Full Pitch Mini-Flat 4-Pin, DIN EN/IEC60747-5-5 Option	Tape and Reel (2500 Units)

#### Note:

The product orderable part number system listed in this table also applies to the FODM121A, FODM121B, FODM121C, FODM124, FODM2701, and FODM2705 products.

## **Marking Information**

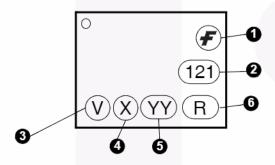
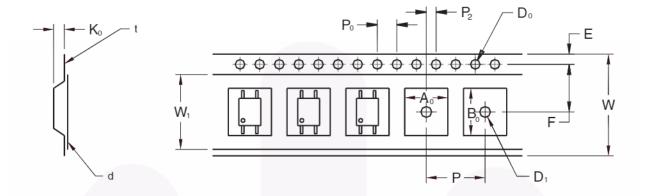


Figure 20. Top Mark

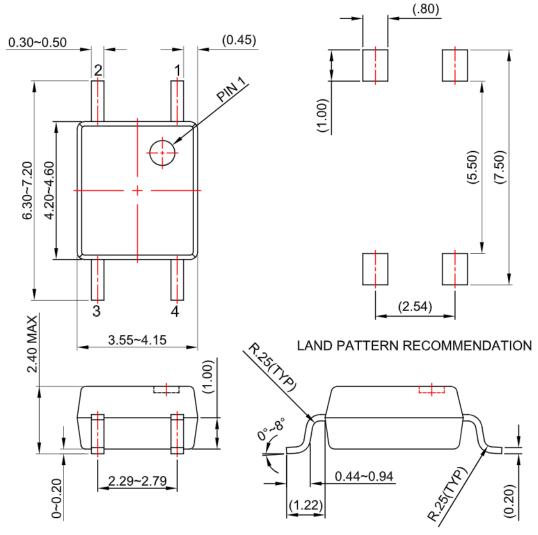
### **Table 1. Top Mark Definitions**

1	Fairchild Logo		
2	Device Number		
3	DIN EN/IEC60747-5-5 Option (only appears on component ordered with this option)		
4	One-Digit Year Code, e.g., "5"		
5	Digit Work Week, Ranging from "01" to "53"		
6	Assembly Package Code		

## **Carrier Tape Specifications**



		2.54 Pitch
Description	Symbol	Dimensions
Tape Width	W	12.00±0.4
Tape Thickness	t	0.35±0.02
Sprocket Hole Pitch	P <sub>0</sub>	4.00±0.20
Sprocket Hole Dia.	D <sub>0</sub>	1.55±0.20
Sprocket Hole Location	E	1.75±0.20
Pocket Location	F	5.50±0.20
	P <sub>2</sub>	2.00±0.20
Pocket Pitch	Р	8.00±0.20
Pocket Dimension	A <sub>0</sub>	4.75±0.20
	B <sub>0</sub>	7.30±0.20
	K <sub>0</sub>	2.30±0.20
Pocket Hole Dia.	D <sub>1</sub>	1.55±0.20
Cover Tape Width	W <sub>1</sub>	9.20
Cover Tape Thickness	d	0.065±0.02
Max. Component Rotation or Tilt		20° max
Devices Per Reel		2500
Reel Diameter		330 mm (13")



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